

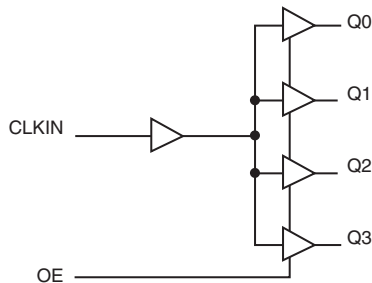
## GENERAL DESCRIPTION

The 830584I is a low skew, general purpose PCI-X 1-to-4 Fanout Buffer and a member of the family of High Performance Clock Solutions from IDT. Guaranteed output and part-to-part skew characteristics make the 830584I ideal for those clock distribution applications demanding well defined performance and repeatability. The 830584I is designed and characterized from -40°C to 85°C for industrial applications and is packaged in an 8 TSSOP package.

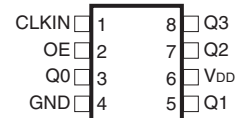
## FEATURES

- General purpose and PCI-X 1:4 clock buffer
- Four single-ended LVCMOS/LVTTL clock outputs
- One single-ended LVCMOS/LVTTL clock input
- Maximum output frequency: 140MHz
- Output enable control (outputs disabled in logic low state)
- Output skew: 100ps (maximum)
- Part-to-part skew: 400ps (maximum)
- Additive phase jitter, RMS: 0.15ps (typical)
- Space-saving 8 lead TSSOP package
- Full 3.3V operating supply mode
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) packages

## BLOCK DIAGRAM



## PIN ASSIGNMENT



**830584I**  
**8-Lead TSSOP**  
 4.40mm x 3.0mm x 0.925mm  
 package body  
**G Package**  
 Top View

**TABLE 1. PIN DESCRIPTIONS**

Number	Name	Type	Description
1	CLKIN	Input	Single-ended clock input reference signal. LVCMOS/LVTTL interface levels.
2	OE	Input	Output enable control input pin. See Table 3, Function Table. LVCMOS / LVTTL interface levels.
3, 5, 7, 8	Q0, Q1, Q2, Q3	Output	Single-ended clock outputs. LVCMOS/LVTTL interface levels.
4	GND	Power	Power supply ground.
6	V <sub>DD</sub>	Power	Positive supply pin.

**TABLE 2. PIN CHARACTERISTICS**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>OUT</sub>	Output Impedance			15		Ω

**TABLE 3. FUNCTION TABLE**

Inputs		Outputs
OE	CLKIN	Q0:Q3
0	0	0
0	1	0
1	0	0
1	1	1

**ABSOLUTE MAXIMUM RATINGS**

Supply Voltage, $V_{DD}$	4.6V
Inputs, $V_I$	-0.5V to $V_{DD} + 0.5V$
Outputs, $V_O$	-0.5V to $V_{DD} + 0.5V$
Package Thermal Impedance, $\theta_{JA}$	121.5°C/W (0 mps)
Storage Temperature, $T_{STG}$	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

**TABLE 4A. RECOMMENDED OPERATING CONDITIONS,  $V_{DD} = 3.3V \pm 0.3V$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Positive Supply Voltage		3.0	3.3	3.6	V
$V_{IH}$	High Level Input Voltage		$0.7 \cdot V_{DD}$			V
$V_{IL}$	Low Level Input Voltage				$0.3 \cdot V_{DD}$	V
$V_I$	Input Voltage		0		$V_{DD}$	V
$I_{OH}$	High-Level Output Current				-24	mA
$I_{OL}$	Low-Level Output Current				24	mA
$T_A$	Operating Free-Air Temperature		-40		85	°C

**TABLE 4B. DC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 0.3V$ ,  $T_A = -40^\circ C$  TO  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical†	Maximum	Units
$V_{IK}$	Input Voltage	$I_I = -18mA$			-1.2	V
$V_{OH}$	Output High Voltage	$I_{OH} = -1mA$	$V_{DD} - 0.2$			V
		$I_{OH} = -24mA$	2			V
		$I_{OH} = -12mA$	2.4			V
$V_{OL}$	Output Low Voltage	$I_{OL} = 1mA$			0.2	V
		$I_{OL} = 24mA$			0.8	V
		$I_{OL} = 12mA$			0.55	V
$I_{OH}$	Output High Current	$V_O = 1V$	-50			mA
		$V_O = 1.65V$		-55		mA
$I_{OL}$	Output Low Current	$V_O = 2V$	60			mA
		$V_O = 1.65V$		70		mA
$I_I$	Input Current	$V_I = 0V$ or $V_{DD}$			$\pm 150$	$\mu A$
$I_{DD}$	Dynamic Current	$f = 67MHz$			37	mA
$C_I$	Input Capacitance	$V_I = 0V$ or $V_{DD}$		3		pF
$C_O$	Output Capacitance	$V_I = 0V$ or $V_{DD}$		3.2		pF

†All typical values are at respective nominal  $V_{DD}$  and 25°C.

**TABLE 5. AC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 0.3V$ ,  $T_A = -40^{\circ}C$  TO  $85^{\circ}C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{clk}$	Clock Frequency; NOTE 1		0		140	MHz
$t_{p_{LH}}$	Propagation Delay, Low to High; NOTE 2		1.8	2.5	3	ns
$t_{p_{HL}}$	Propagation Delay, High to Low; NOTE 2		1.8	2.4	3	ns
$t_{sk(o)}$	Output Skew; NOTE 3, 4			50	100	ps
$t_{sk(p)}$	Pulse Skew	140MHz			170	ps
$t_{sk(pr)}$	Process Skew			200	300	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 4, 5			250	400	ps
$t_{jit}$	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter section	140MHz, Integration Range: 10kHz – 20MHz		0.15		ps
$T_{high}$	CLK High Time	66MHz	6			ns
		140MHz	3			ns
$T_{low}$	CLK Low Time	66MHz	6			ns
		140MHz	3			ns
$t_R$	Output Rise Slew Rate <sup>†</sup>	$0.2V_{DD}$ to $0.6V_{DD}$	1.5	2.7	4	V/ns
$t_F$	Output Fall Slew Rate <sup>†</sup>	$0.6V_{DD}$ to $0.2V_{DD}$	1.5	2.7	4	V/ns

<sup>†</sup>All typical values are at respective nominal  $V_{DD}$ .

<sup>†</sup>This symbol is according to PCI-X terminology.

NOTE 1: Switching characteristics over recommended ranges of supply voltages and operating free-air temperature,  $C_L = 10pF$ ,  $V_{DD} = 3.3V \pm 0.3V$ .

NOTE 2: Measured from  $V_{DD}/2$  of the input to  $V_{DD}/2$  of the output.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at  $V_{DD}/2$ .

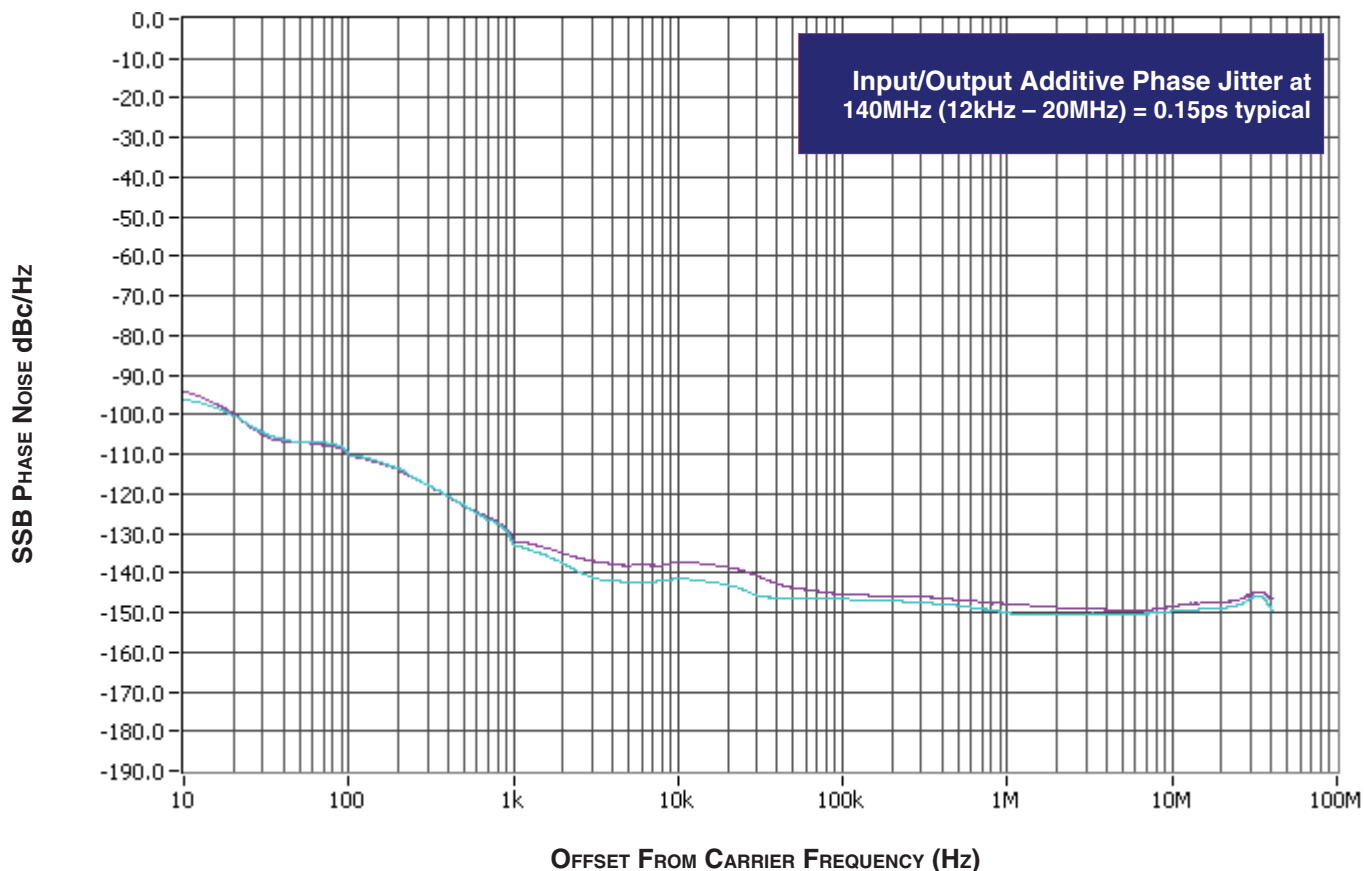
NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 5: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of input on each device, the output is measured at  $V_{DD}/2$ .

## ADDITIVE PHASE JITTER

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the **dBc Phase Noise**. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels

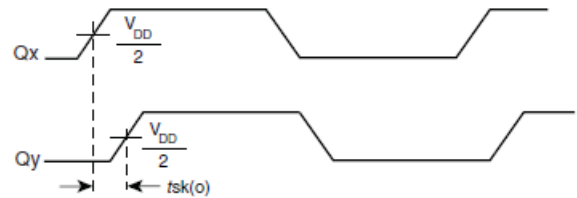
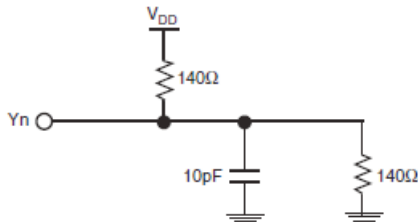
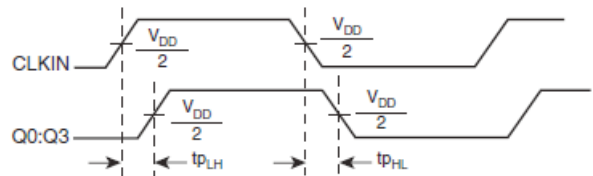
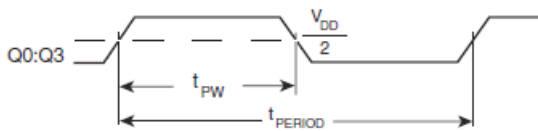
(dBm) or a ratio of the power in the 1Hz band to the power in the fundamental. When the required offset is specified, the phase noise is called a **dBc** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



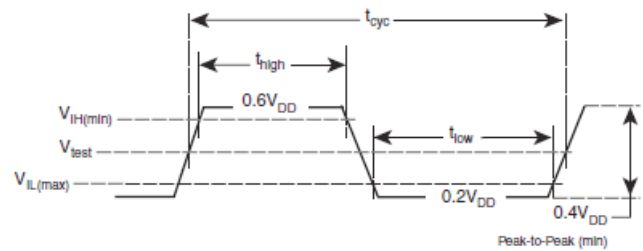
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device.

This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

# PARAMETER MEASUREMENT INFORMATION

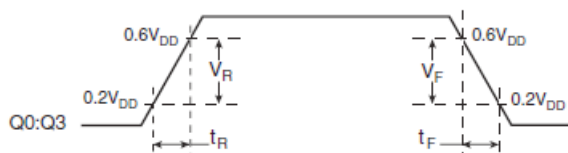

**3.3V CORE/3.3V OUTPUT LOAD AC TEST CIRCUIT**
**OUTPUT SKEW**

**PART-TO-PART SKEW**
**PROPAGATION DELAY**


$$odc = \frac{t_{PW}}{t_{PERIOD}} \times 100\%$$


**OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD**

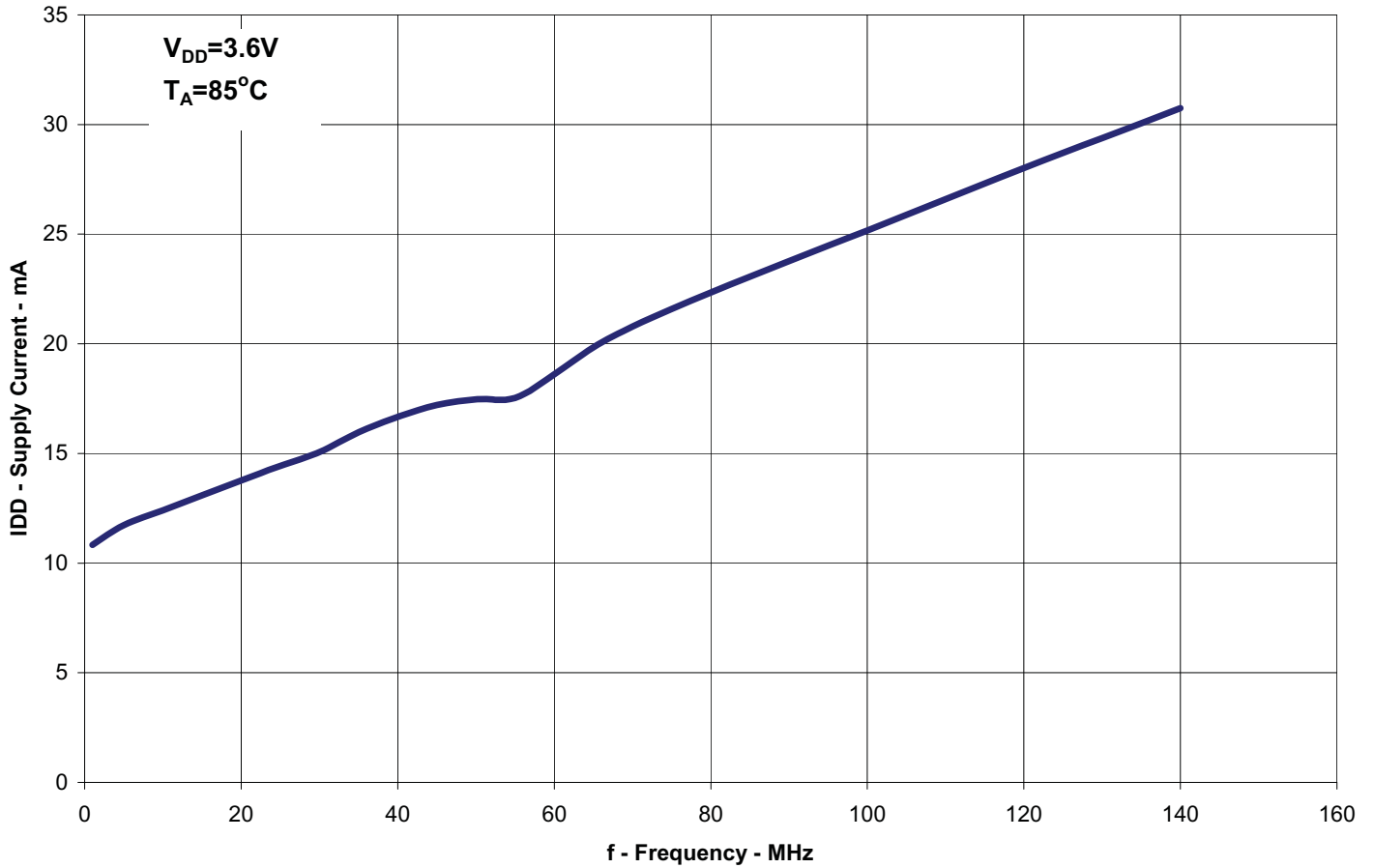
Parameter	Value	Unit
$V_{IH(min)}$	$0.5V_{DD}$	V
$V_{IL(max)}$	$0.35V_{DD}$	V
$V_{test}$	$0.4V_{DD}$	V

NOTE: All parameters are according to PCI-X 1.0 specifications


**OUTPUT RISE/FALL SLEW RATES**
**CLOCK WAVEFORM**

## PARAMETER MEASUREMENT INFORMATION, CONTINUED

Supply Current  
vs  
Frequency



## APPLICATION INFORMATION

### RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

#### INPUTS:

##### OE INPUT

The OE pin must be tied either HIGH or LOW. Do not leave floating.

#### OUTPUTS:

##### LVC MOS OUTPUTS

All unused LVC MOS outputs can be left floating. We recommend that there is no trace attached.

## RELIABILITY INFORMATION

TABLE 6.  $\theta_{JA}$  vs. AIR FLOW TABLE FOR 8 LEAD TSSOP

$\theta_{JA}$ by Velocity (Meters per Second)			
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	121.5°C/W	117.3°C/W	115.3°C/W

#### TRANSISTOR COUNT

The transistor count for 830584I is: 307



## PACKAGE OUTLINE - G SUFFIX FOR 8 LEAD TSSOP

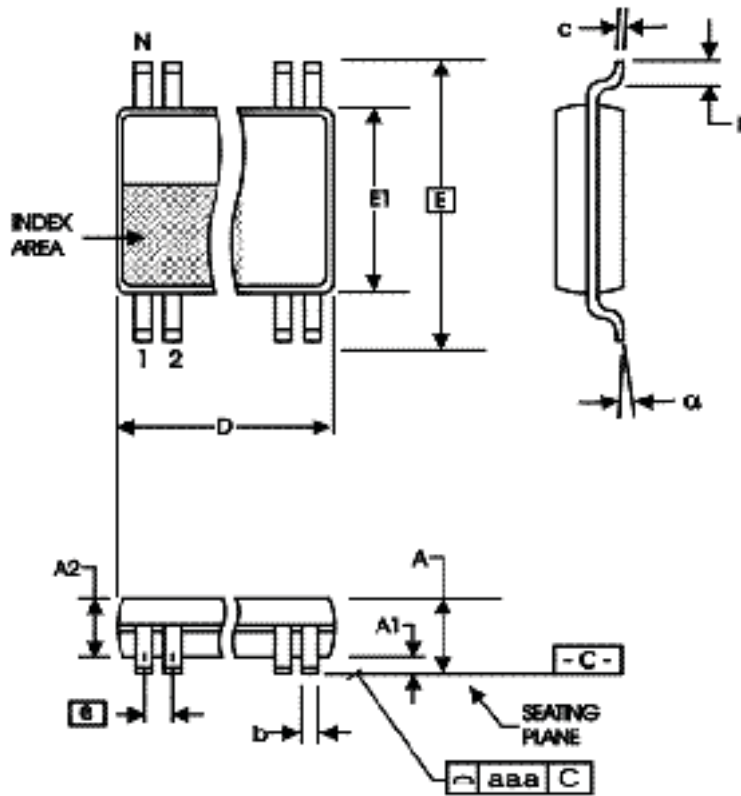


TABLE 7. PACKAGE DIMENSIONS

SYMBOL	Millimeters	
	Minimum	Maximum
N	8	
A	--	1.20
A1	0.05	0.15
A2	0.80	1.05
b	0.19	0.30
c	0.09	0.20
D	2.90	3.10
E	6.40 BASIC	
E1	4.30	4.50
e	0.65 BASIC	
L	0.45	0.75
$\alpha$	0°	8°
aaa	--	0.10

Reference Document: JEDEC Publication 95, MO-153

**TABLE 8. ORDERING INFORMATION**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
830584AGILF	84AIL	8 lead "Lead-Free" TSSOP	tube	-40°C to 85°C
830584AGILFT	84AIL	8 lead "Lead-Free" TSSOP	tape & reel	-40°C to 85°C

REVISION HISTORY SHEET				
Rev	Table	Page	Description of Change	Date
B	T4B	3	DC Characteristics Table - corrected Input Current typo from $\pm 5\mu\text{A}$ max. to $\pm 150\mu\text{A}$ max.	3/18/08
B	T8	1 10	General Description - removed ICS Chip and HiPerClockS. Ordering Information - removed ICS under Part/Order Number. Removed 2500 for Tape & Reel. Removed LF Note below table. Updated Header and Footer.	12/16/15



Corporate Headquarters  
6024 Silver Creek Valley Road  
San Jose, CA 95138 USA  
[www.IDT.com](http://www.IDT.com)

Sales  
1-800-345-7015 or 408-284-8200  
Fax: 408-284-2775  
[www.IDT.com/go/sales](http://www.IDT.com/go/sales)

Tech Support  
[www.idt.com/go/support](http://www.idt.com/go/support)

DISCLAIMER Integrated Device Technology, Inc. (IDT) reserves the right to modify the products and/or specifications described herein at any time, without notice, at IDT's sole discretion. Performance specifications and operating parameters of the described products are determined in an independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in applications involving extreme environmental conditions or in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are trademarks or registered trademarks of IDT and its subsidiaries in the United States and other countries. Other trademarks used herein are the property of IDT or their respective third party owners.

For datasheet type definitions and a glossary of common terms, visit [www.idt.com/go/glossary](http://www.idt.com/go/glossary).

Copyright ©2015 Integrated Device Technology, Inc. All rights reserved.